

Slide 1: What Is MEMS?

- MEMS = Micro-Electro-Mechanical Systems.
- Devices combine mechanical structures, sensors/actuators, and electronics.
- Typical size: micrometers to millimeters.
- Materials: silicon, silicon dioxide, silicon nitride, metals, polymers.

Examples:

- Accelerometers and gyroscopes
- Pressure sensors
- Microphones
- RF switches and resonators

Slide 2: Why MEMS Is Important

MEMS enables:

- High-volume, low-cost sensing in consumer electronics.
- Harsh-environment sensing in automotive and industrial systems.
- Miniaturized diagnostics in medical and biotech applications.

Value proposition:

- Small form factor
- Low power operation
- Batch fabrication using semiconductor-style processes

Slide 3: Core MEMS Building Blocks

Mechanical elements:

- Beams, membranes, comb fingers, masses, anchors

Transduction mechanisms:

- Capacitive (most common in inertial MEMS)
- Piezoresistive
- Piezoelectric
- Thermal / optical (application-specific)

Readout and interface:

- Analog front-end (AFE)
- ADC and digital filtering
- Calibration and compensation algorithms

Slide 4: Surface Micromachining

Concept:

- Build structures layer-by-layer on wafer surface.
- Use sacrificial layers to create air gaps and movable parts.

Typical flow:

- 1) Deposit sacrificial layer
- 2) Deposit structural layer (e.g., polysilicon)
- 3) Pattern and etch
- 4) Release sacrificial material
- 5) Dry to avoid stiction

Pros:

- Good CMOS compatibility
- Fine feature control

Cons:

- Limited structural thickness

Slide 5: Bulk Micromachining

Concept:

- Sculpt the wafer itself (deep cavities, diaphragms, high-aspect structures).

Key methods:

- Wet etch (KOH, TMAH)
- Deep reactive ion etch (DRIE / Bosch process)
- SOI-based etching for thickness control

Pros:

- Thick, robust structures
- Excellent for pressure sensors and inertial masses

Cons:

- Process complexity and stress management challenges

Slide 6: MEMS + CMOS Integration

Integration strategies:

- Monolithic: MEMS and CMOS on same die
- Hybrid/multi-chip: separate dies in one package
- Wafer-level bonding approaches for cavity sealing

Tradeoffs:

- Monolithic gives compact systems but stricter thermal/process budgets.
- Hybrid gives process flexibility but may increase parasitics and assembly cost
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Design goal:

Optimize performance, yield, and cost simultaneously.

Slide 7: Packaging and Reliability

MEMS packaging is often part of the device physics.

Critical packaging functions:

- Mechanical protection
- Controlled cavity pressure (vacuum or gas)
- Environmental isolation (moisture/particles)
- Electrical interconnect and thermal path

Reliability topics:

- Stiction and wear
- Drift and bias instability
- Shock/vibration survivability
- Temperature and humidity effects

Slide 8: Test and Calibration

Production test includes:

- Electrical continuity and leakage
- Sensor response linearity and sensitivity
- Noise density and bandwidth checks
- Self-test actuator verification (when available)

Calibration includes:

- Offset/bias correction
- Scale-factor trimming
- Temperature compensation coefficients

Output quality metric examples:

- Bias stability (gyro)
- g-sensitivity and cross-axis sensitivity (accelerometer)

Slide 9: Application Snapshots

Consumer:

- Phone IMU (accelerometer + gyroscope)
- MEMS microphone arrays

Automotive:

- Airbag accelerometers
- Tire pressure monitoring sensors
- In-cabin sensing

Industrial/medical:

- Vibration monitoring
- Pressure/flow sensing
- Microfluidic lab-on-chip interfaces

Slide 10: Summary and Next Steps

Key takeaways:

- MEMS combines mechanics and microfabrication for scalable sensing/actuation.
- Surface and bulk micromachining serve different geometry and integration needs
- Packaging, testing, and calibration are central to real-world performance.
- Co-design across device, circuit, and package is essential.

Recommended repository reading:

- [docs/04-mems-surface-micromachining/device-examples.md](#)
- [docs/05-mems-bulk-micromachining/pressure-sensors.md](#)
- [docs/08-integrated-mems-cmos/integration-strategies.md](#)
- [docs/07-testing-yield/reliability-testing.md](#)

End of deck.